

SieveWare



SieveWare, the software for particle size analyses, exceeds manual evaluation in many aspects, due to the fact that the software is able to automatically control the necessary measurement and weighing procedures – from the registration of the weight of the sieve up to the evaluation of the data.

All available parameters as well as the characteristics, which may have to be calculated, can be entered.

The program accepts automatic and manual data entries from both scale and sieve systems. The Octagon 200CL can be automatically controlled with SieveWare via RS232 communication.

SieveWare calculates all common particle distributions as well as the characteristic values of the particle size, thus making it possible to present the results in standard presentation forms, such as tables and charts. Cumulative throughput or residual values, distribution density and histograms can be included in the standard particle size distributions.

All measured data can be printed, saved and exported as tables and charts.

Advantages

- Automatic registration, evaluation and administration of measurement data
- Logical, self-explanatory interface
- Measurement protocol in accordance with different standards
- Complex transformation into charts and tables
- Data link to different measurement instruments
- Automatic detection and configuration of common analytical scales
- Comprehensive data export
- Comprehensive help texts & detailed manual



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General Information

Windows® interface	Windows® 2000/XP/Vista (others on request)
ASTM and Tyler Mesh	x
Password protection for sieve analysis	x
Serial no. for sieves	x
Sieve analysis with	
▪ nominal mesh size	x
▪ actual mesh size	x
Automatic simultaneous data transfer	x
Administration of measurement data	unlimited
Data import and export	x
PDF manual on CD-ROM	x
Measurement protocol (according to DIN 66165)	x
Language selection English/German	x

Tables	
Throughput values Q3 (x)	x
Residual values (1-Q3(x))	x
Fraction p3	x
Fraction Δm (proportional masses)	x
Distribution density q3(x)	x
log. distribution density q3*(x)	x
Actual mesh size	x

Diagram	
Combined representation of several analyses	x
Curve representation	x

Graphic presentation	
▪ x-axis	lin, log
▪ y-axis	lin, log, RRSB
Windowing (Zoom)	x
Cumulative curve (throughput) Q3 (x)	x
Residual curve (1-Q3 (x))	x
Fraction p3/histogram	x
Lin. Division density q3(x)	x
Log. Division density q3*(x)	x
Trend analysis	x
Limit value graph with specifications limits	x
2 representation possibilities (including right y-axis)	x
Reference particles (registration of external particle size division)	x

Parameters	
Fineness parameters, 3 values Q3 (x)	x
Quantile particle size, 3 values x (Q3)	x
RRSB parameters	x
Sauter mean diameter X St	x
Splinter value	x

Specific surface	
▪ volume related Sv	x
▪ mass related Sm	x
Unequal grade of granularity	x
AFS particle fineness No.	x